

Search Notes

Application/Control No.

10/791,135

Examiner

Jinhee J. Lee

Applicant(s)/Patent under
Reexamination

CHEN ET AL.

Art Unit

2831

SEARCHED

Class	Subclass	Date	Examiner
174	100	3/31/2005	LEE
↓	72A	↓	↓
↓	99R	↓	↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
174	as above	3/31/2005	LEE

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East text search attached	3/31/2005	LEE